


<b>Search Notes</b>  	<b>Application/Control No.</b>  10525593	<b>Applicant(s)/Patent Under Reexamination</b>  TANAKA, KATSUZO
	<b>Examiner</b>  RICHARD CHAN	<b>Art Unit</b>  2618

SEARCHED			
Class	Subclass	Date	Examiner
455	550.1, 50, 575.1	7/16/08	RC
379	368, 433.07, 433.06	7/16/08	RC

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted Ed Urban	07/16/08	RC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
455	550.1, 575.1	7/1/086	RC